

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. An acceptance or concern response should be submitted to ADI promptly. Any requests for samples of changed material or additional information must be made within 30 days of the notification. In accordance with JEDEC Standard 046, customers should acknowledge receipt of the PCN within 30 days of the PCN delivery. ADI contact information is listed below. Note: Revised fields are indicated by a red field name. See Appendix B for revision history.

Lack of acknowledgment of the PCN within 30 days constitutes acceptance of the change. After the acknowledgment, a lack of additional requests within 90 days constitutes acceptance of the change.

PCN Title:	Qualification of Analog Devices, Inc. Camas, WA Wafer Fabrication Site for CBCMOS2 Processes
Publication Date:	04-Aug-2026
Effectivity Date:	06-Nov-2026 <i>(earliest date that a customer could expect to receive changed material)</i>
Comments:	

DESCRIPTION OF CHANGE:

Qualification of Analog Devices, Camas, WA, USA wafer fabrication site from Analog Devices, Wilmington MA, USA for CBCMOS2 processes, applying to AEC automotive products AD8202 and AD8203.

REASON FOR CHANGE:

Leveraging the existing qualified process at our Analog Devices Camas, WA Fab ensures a reliable and continuous supply for our customers securing their needs well into the future.

The affected products will be manufactured using ADI specified manufacturing flows, materials, process controls, and monitors ensuring no degradation of quality and reliability performance.

IMPACT OF THE CHANGE (POSITIVE OR NEGATIVE) ON FIT, FORM, FUNCTION & RELIABILITY:

There is no expected impact to fit, form, function or reliability.

PRODUCT IDENTIFICATION (THIS SECTION WILL DESCRIBE HOW TO IDENTIFY THE CHANGED MATERIALS):

Traceability will be maintained via standard ADI lot traceability.

SUMMARY OF SUPPORTING INFORMATION:

- Qualification has been performed per AEC-Q100, Stress Test Qualification for Integrated Circuits. See attached Qualification Results.

SUPPORTING DOCUMENTS:

Attachment 1: Type: Qualification Results Summary

[ADI_PCN_2026-0074_QUALIFICATION_OF_ADI_CAMAS_WAFER_FAB_CBCMOS2_V1.pdf](#)

Attachment 2: Type: Delta Qualification Matrix

[ADI_PCN_2026-0074_DELTA-QUALIFICATION-MATRIX-ZVEI-5_3_0_V1_V1.xlsm](#)

ADI CONTACT INFORMATION:

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:	Europe:	Japan:	Korea:	Rest of Asia:
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PCN_Americas@analog.com	PCN_Europe@analog.com	PCN_Japan@analog.com	PCN_Korea@analog.com	PCN_ROA@analog.com
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APPENDIX A - IMPACTED ITEMS, SEE CSV PN LISTING IN PCN ZIP FILE

APPENDIX B – REVISION HISTORY:

Rev	Publish	Effectivity Date	Rev Description
Rev. -	04-Aug-2026	06-Nov-2026	